Notice of References Cited Application/Control No. 09/544,289 Applicant(s)/Patent Under Reexamination HIYOSHI, TAKAYUKI Examiner Hai C. Pham 2861 Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,121,993	09-2000	Maekawara et al.	347/236
	В	US-			
	С	US-		·	
	D	US-			
	Ę	US-			
	F	US-			
	G	US-			
	Н	US-			
	١	US-			
	J	US-			
	к	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	P.					
	Q					
	R	_				·
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	٧					
	w					
	х					

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.